Search Notes



Application/Control	No.	

10/767,614

Thomas D. Lee

Examiner

Applicant(s)/Patent under Reexamination

OGAWA, HIDEHIKO

Art Unit

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Class	Subclass	Date	Examiner
358	1.15, 402, 440	6/6/2005	TDL
379	100.01	6/6/2005	TDL
379	100.08	6/6/2005	TDL
379	100.13	6/6/2005	TDL
379	100.17	6/6/2005	TDL
updated		9/14/2005	TDL
updated		12/7/2005	TDL

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